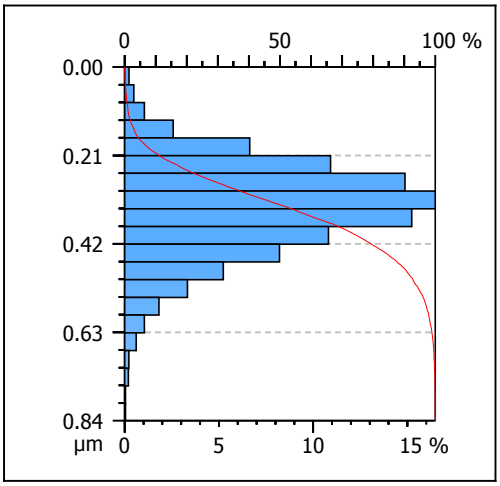
TSS Analysis of
2D Surface Roughness Measurement

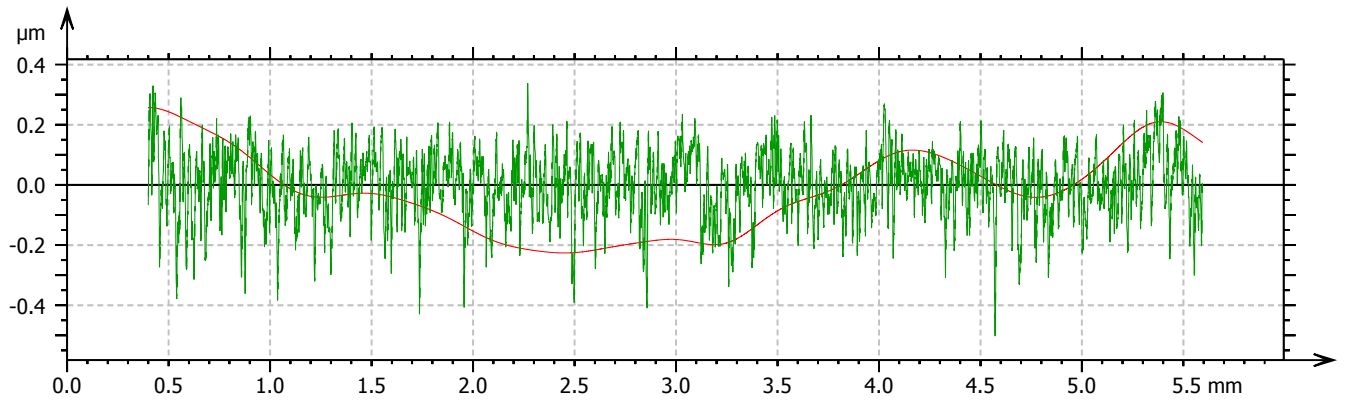
Name: Project and Measured Item Names here **Date:** 20-Dec-22



ISO 4287

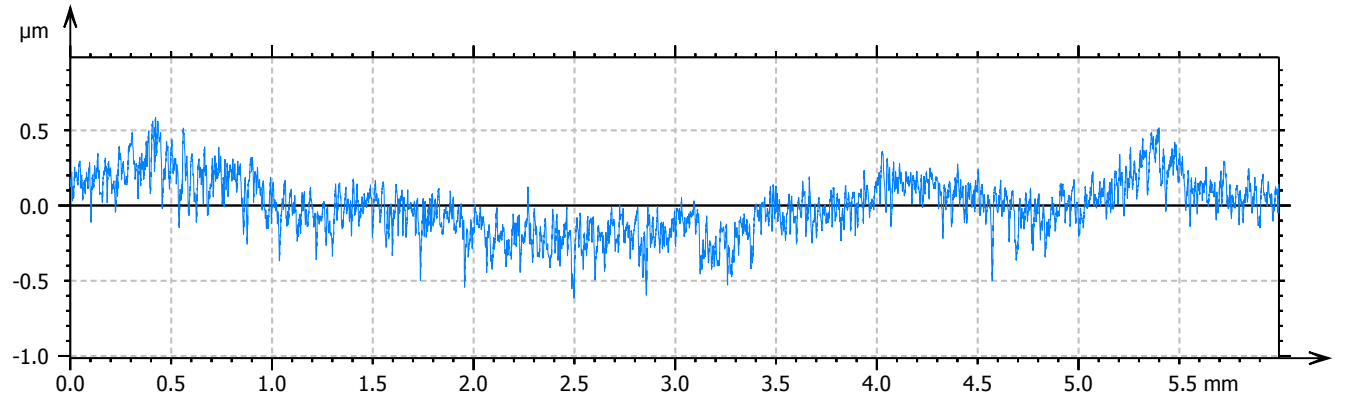
Amplitude parameters - Roughness profile			
Ra	0.086	µm	*Gaussian filter, 0.8 mm*
Rp	0.275	µm	*Gaussian filter, 0.8 mm*
Rsk	-0.445		*Gaussian filter, 0.8 mm*
Rz	0.660	µm	*Gaussian filter, 0.8 mm*
Rq	0.109	µm	*Gaussian filter, 0.8 mm*
Rt	0.840	µm	*Gaussian filter, 0.8 mm*
Rv	0.385	µm	*Gaussian filter, 0.8 mm*
Rc	0.248	µm	*Gaussian filter, 0.8 mm, ISO 4287 w/o amendment 2*
Material ratio parameters - Roughness profile			
Rmr (Rz/4)	54.4	%	*c = Rz/4 µm under the ref, 5%, Gaussian filter, 0.8 mm*

Filtered profiles - Leveled (Least squares method)



Information	
Profile	Roughness profile & Waviness profile
Filter settings	Gaussian filter, cut-off 0.800 mm

Profile curve - 17709 Test ED Rod preA 9o



Parameters	Value	Unit
Length	5.99	mm

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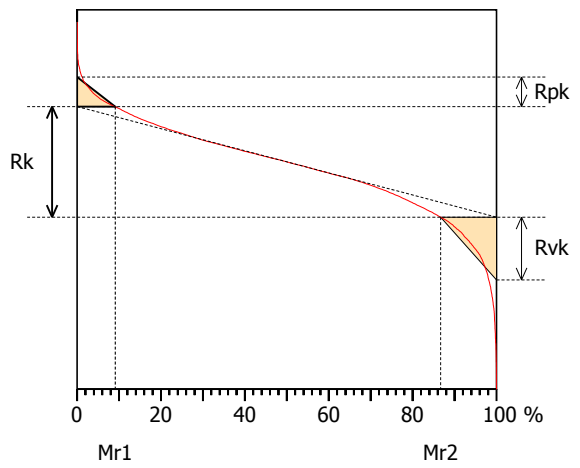

Information	
Filter settings	Gaussian filter, 0.800 mm.

Parameters	Value	Unit
Rk	0.245	µm
Rpk	0.0653	µm
Rvk	0.139	µm
Mr1	9.09	%
Mr2	86.7	%
A1	2.97	µm²/mm
A2	9.25	µm²/mm
Rpk*	0.214	µm
Rvk*	0.380	µm